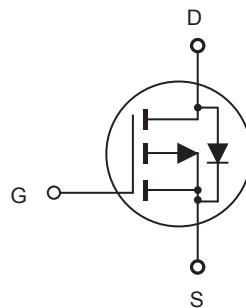


**P-Channel Enhancement Mode Field Effect Transistor**

PRELIMINARY

**FEATURES**

- -60V, -36A,  $R_{DS(ON)} = 20m\Omega$  @  $V_{GS} = -10V$ .  
 $R_{DS(ON)} = 26m\Omega$  @  $V_{GS} = -4.5V$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handing capability.
- RoHS compliant.
- TO-251 & TO-252 package.

**ABSOLUTE MAXIMUM RATINGS**  $T_C = 25^\circ C$  unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	$V_{DS}$	-60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	-36	A
Drain Current-Pulsed <sup>a</sup>	$I_{DM}$	-144	A
Maximum Power Dissipation @ $T_C = 25^\circ C$ - Derate above $25^\circ C$	$P_D$	48 0.38	W W/ $^\circ C$
Operating and Store Temperature Range	$T_J, T_{stg}$	-55 to 150	$^\circ C$

**Thermal Characteristics**

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{JC}$	2.6	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient	$R_{JA}$	50	$^\circ C/W$



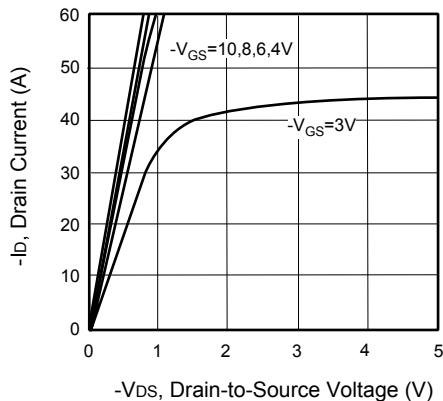
# CED6185/CEU6185

## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

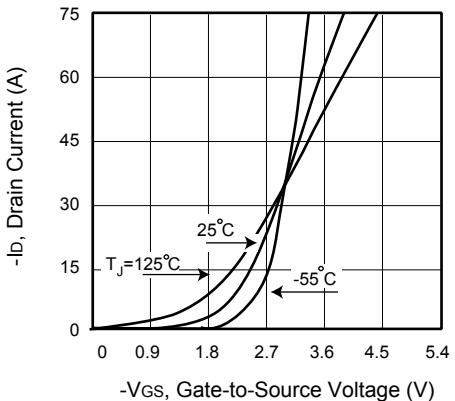
Parameter	Symbol	Test Condition	Min	Typ	Max	Units
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-60			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = -60\text{V}, V_{\text{GS}} = 0\text{V}$			-1	$\mu\text{A}$
Gate Body Leakage Current, Forward	$I_{\text{GSSF}}$	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
Gate Body Leakage Current, Reverse	$I_{\text{GSSR}}$	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$			-100	nA
<b>On Characteristics<sup>b</sup></b>						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = -250\mu\text{A}$	-1		-3	V
Static Drain-Source On-Resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}} = -10\text{V}, I_D = -20\text{A}$		16	20	$\text{m}\Omega$
		$V_{\text{GS}} = -4.5\text{V}, I_D = -20\text{A}$		19	26	$\text{m}\Omega$
<b>Dynamic Characteristics<sup>c</sup></b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = -25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		2845		pF
Output Capacitance	$C_{\text{oss}}$			295		pF
Reverse Transfer Capacitance	$C_{\text{rss}}$			165		pF
<b>Switching Characteristics<sup>c</sup></b>						
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}} = -48\text{V}, I_D = -20\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GEN}} = 6\Omega$		18	26	ns
Turn-On Rise Time	$t_r$			10	8	ns
Turn-Off Delay Time	$t_{\text{d(off)}}$			115	90	ns
Turn-Off Fall Time	$t_f$			38	12	ns
Total Gate Charge	$Q_g$	$V_{\text{DS}} = -48, I_D = -20\text{A}, V_{\text{GS}} = -4.5\text{V}$		38	29.4	nC
Gate-Source Charge	$Q_{\text{gs}}$			8		nC
Gate-Drain Charge	$Q_{\text{gd}}$			18		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward Current	$I_S$				-36	A
Drain-Source Diode Forward Voltage <sup>b</sup>	$V_{\text{SD}}$	$V_{\text{GS}} = 0\text{V}, I_S = -20\text{A}$			-1.2	V

Notes :

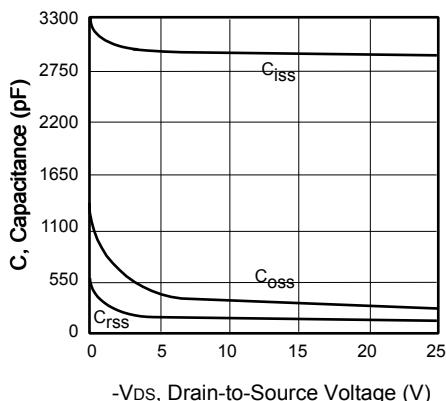
- a.Repetitive Rating : Pulse width limited by maximum junction temperature.
- b.Pulse Test : Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
- c.Guaranteed by design, not subject to production testing.



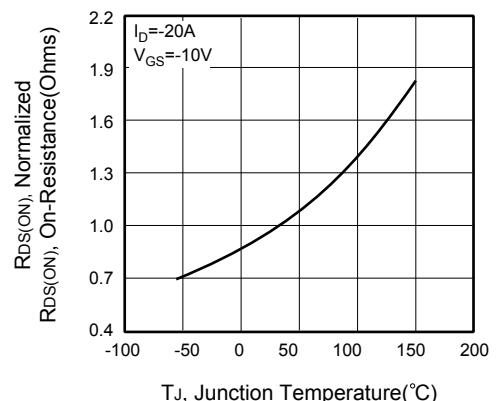
**Figure 1. Output Characteristics**



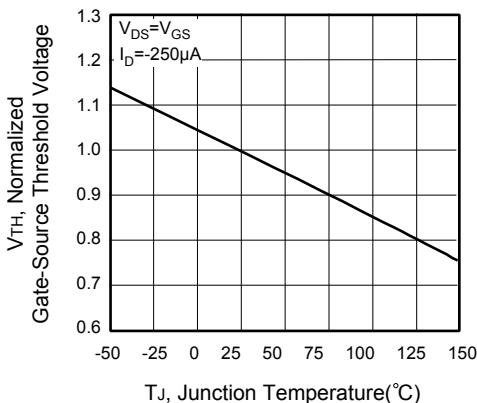
**Figure 2. Transfer Characteristics**



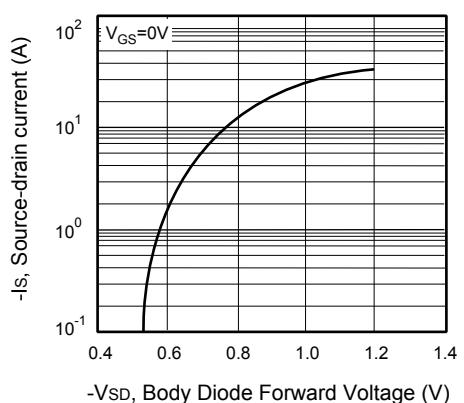
**Figure 3. Capacitance**



**Figure 4. On-Resistance Variation with Temperature**



**Figure 5. Gate Threshold Variation with Temperature**



**Figure 6. Body Diode Forward Voltage Variation with Source Current**

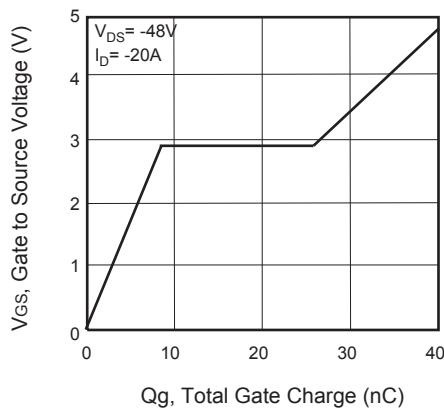


Figure 7. Gate Charge

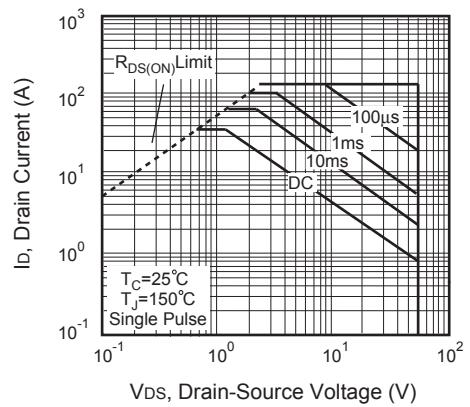


Figure 8. Maximum Safe Operating Area

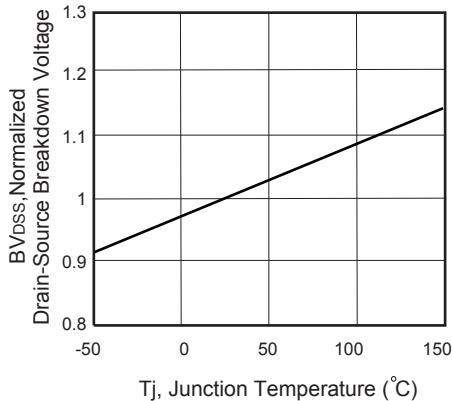


Figure 9. Breakdown Voltage Variation VS Temperature

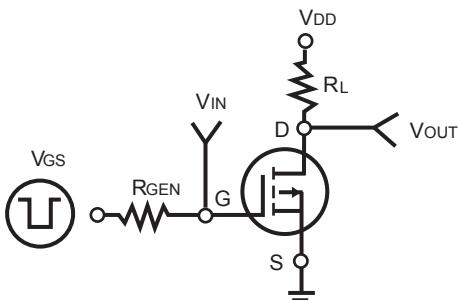


Figure 10. Switching Test Circuit

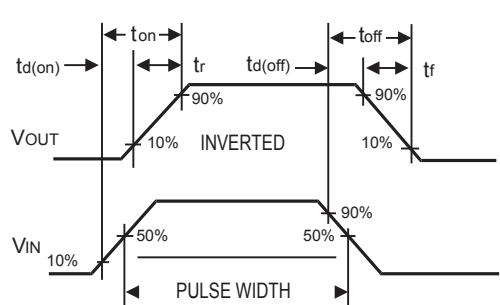
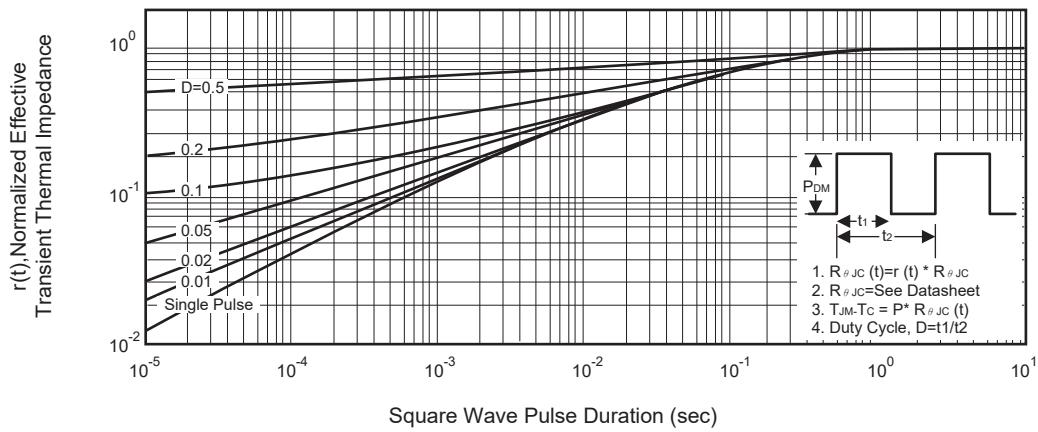


Figure 11. Switching Waveforms

**Figure 12. Normalized Thermal Transient Impedance Curve**